

METHOD FOR PRODUCING TEST PATTERNS FOR TESTING AN  
INTEGRATED CIRCUIT

ABSTRACT

5        A test pattern generation flow has a stimulus and a device under test  
(DUT) that operate together through a test bench. The test bench monitors and  
collects all the data necessary to generate a test program. This information is  
presented as a captured simulation that allows for ease of generating test  
software, as well as other simulations such as fault simulation and virtual test  
10      simulation. The complete and convenient information can be utilized to  
automate the development and/or easily manually develop and debug the test  
software.